

<p>B/O Form PTO-1449</p> <p>U.S. Department of Commerce Patent and Trademark Office</p> <p>Information Disclosure Statement by Applicant</p>	<p>Atty. Docket Number WOLF3003/JEK</p>	<p>Serial Number 10/535,409</p>
	<p>Applicant Wolfgang RAUSCHER</p>	
	<p>Filing Date May 18, 2005</p>	<p>Group 2624</p>

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U.S. Patent Documents

Foreign Patent Documents

Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

		"Pattern Classification: A Unified View of Statistical and Neural Approaches", J. Schurmann, Daimler-Benz Research Center Ulm, John Wiley & Sons, Inc., 1996, pages 62 and 66
		"Technische Bildverarbeitung - Maschinelles Sehen", B. Jahne, R. Massen, B. Nickolay, H. Scharfenberg, Springer-Verlag Berlin, 1995, pages 80 and 81
		"Image Based Measurement Systems", Ferdinand van der Heijden, University of Twente, The Netherlands, John Wiley & Sons, Inc., 1995, pages 131, 132, 134, 135, 142 and 175

Examiner

/Claire Wang/

Date Considered

12/19/2008

EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /CW/